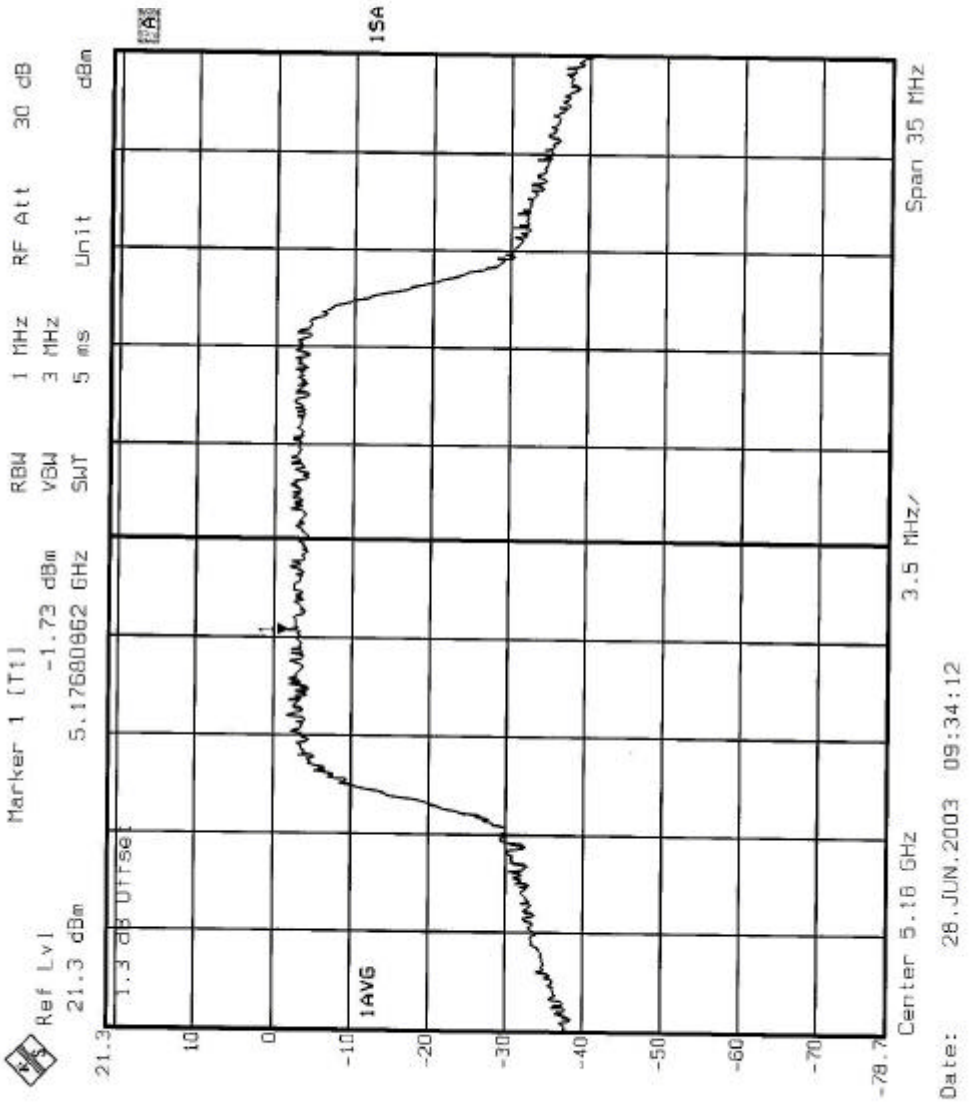
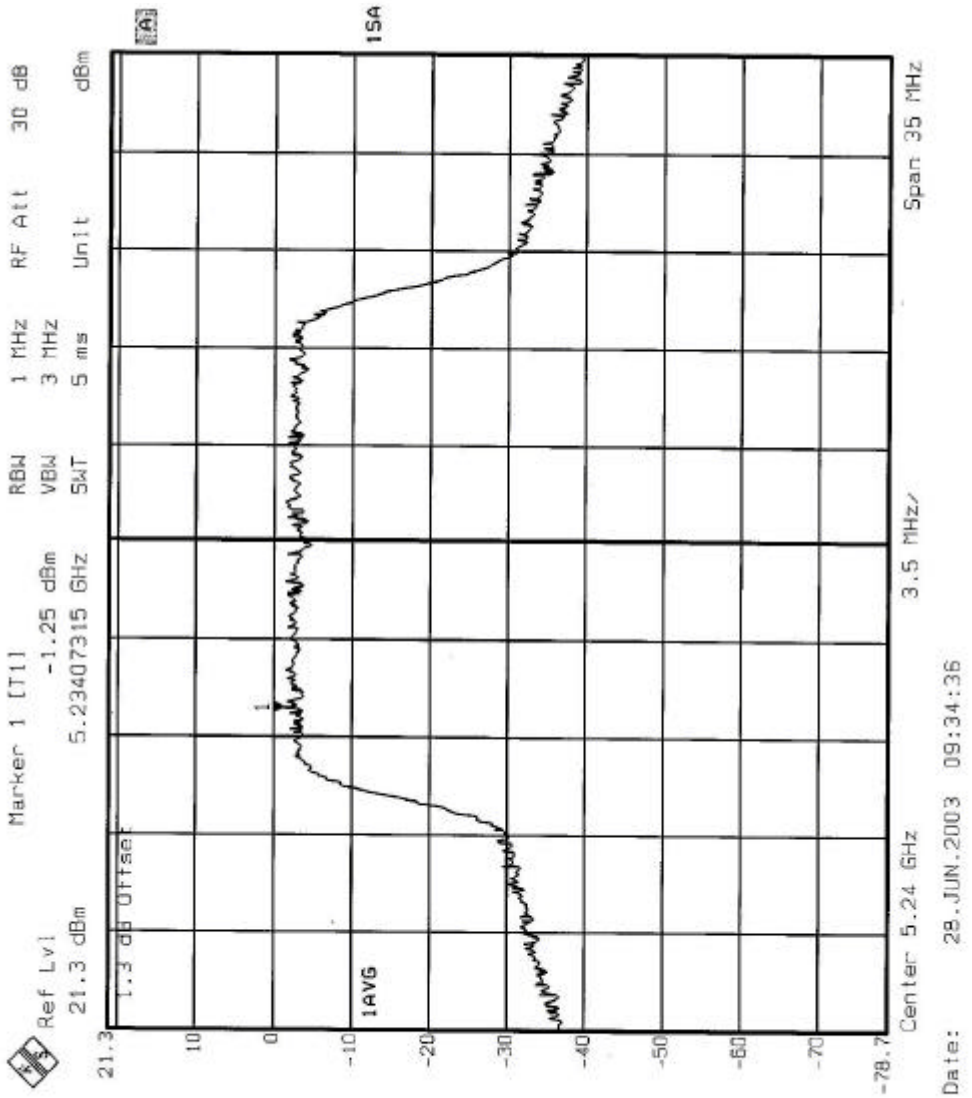
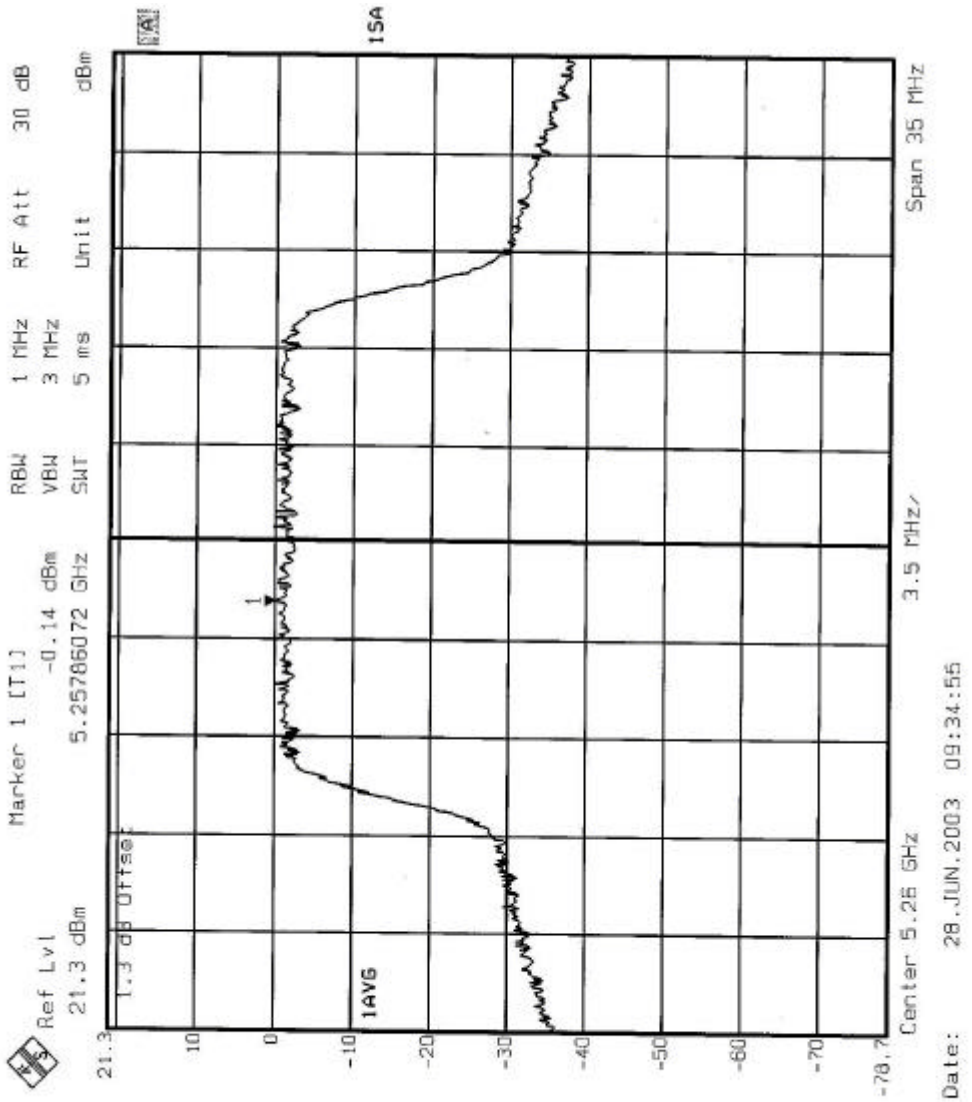
CHANNEL 1


Marker 1 [T1]
-1.73 dBm
5.17680862 GHz
RBW 1 MHz
VBW 3 MHz
SWT 5 ms
RF Att 30 dB
Unit dBm
Ref Lvl
21.3 dBm
1.3 dB Offset
1AVG
1SA
Center 5.18 GHz
3.5 MHz/
Span 35 MHz
Date: 28.JUN.2003 09:34:12

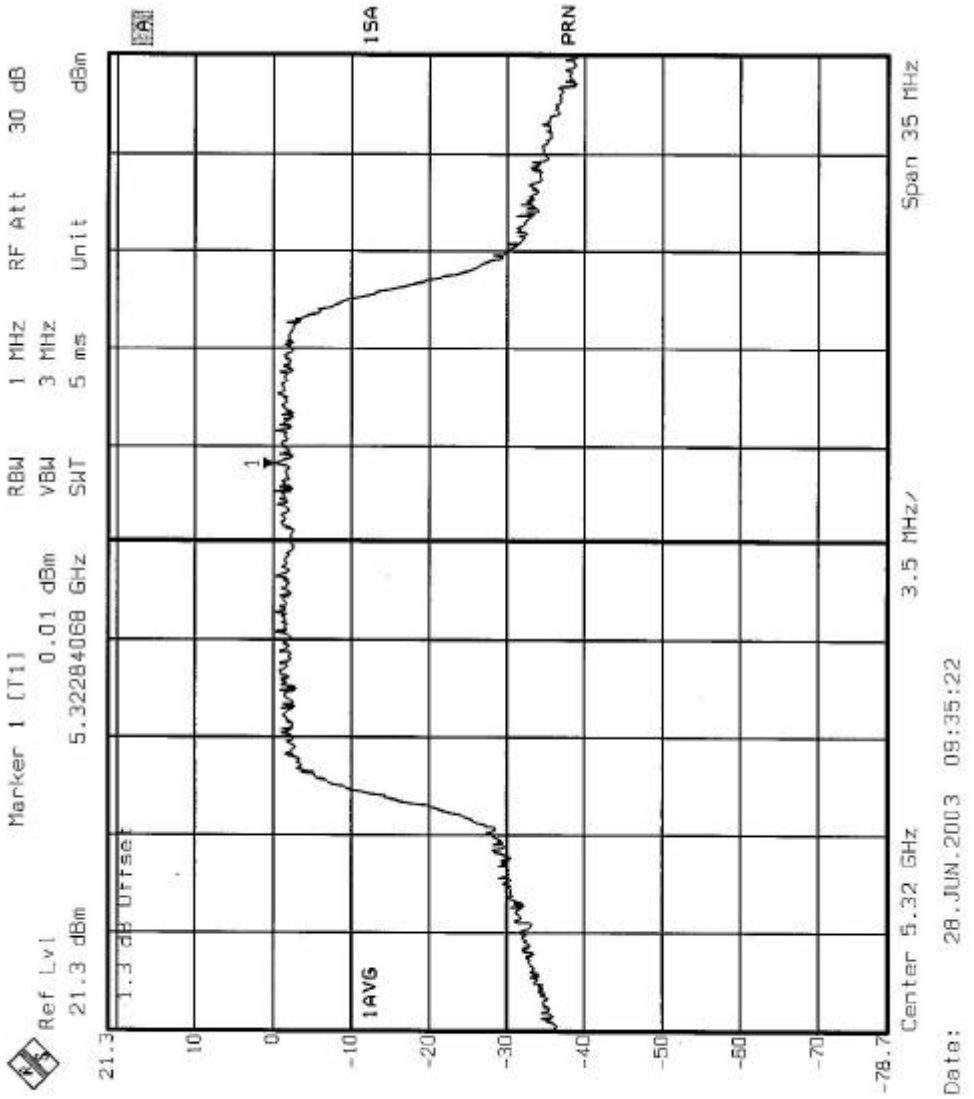
CHANNEL 4


Ref Lvl
21.3 dBm
1.3 dB Offset
Marker 1 [T1]
-1.25 dBm
5.23407315 GHz
RBW 1 MHz
VBW 3 MHz
SWT 5 ms
RF Att 30 dB
Unit dBm
1SA
1AVG
Center 5.24 GHz
3.5 MHz/
Span 35 MHz
Date: 28.JUN.2003 09:34:36

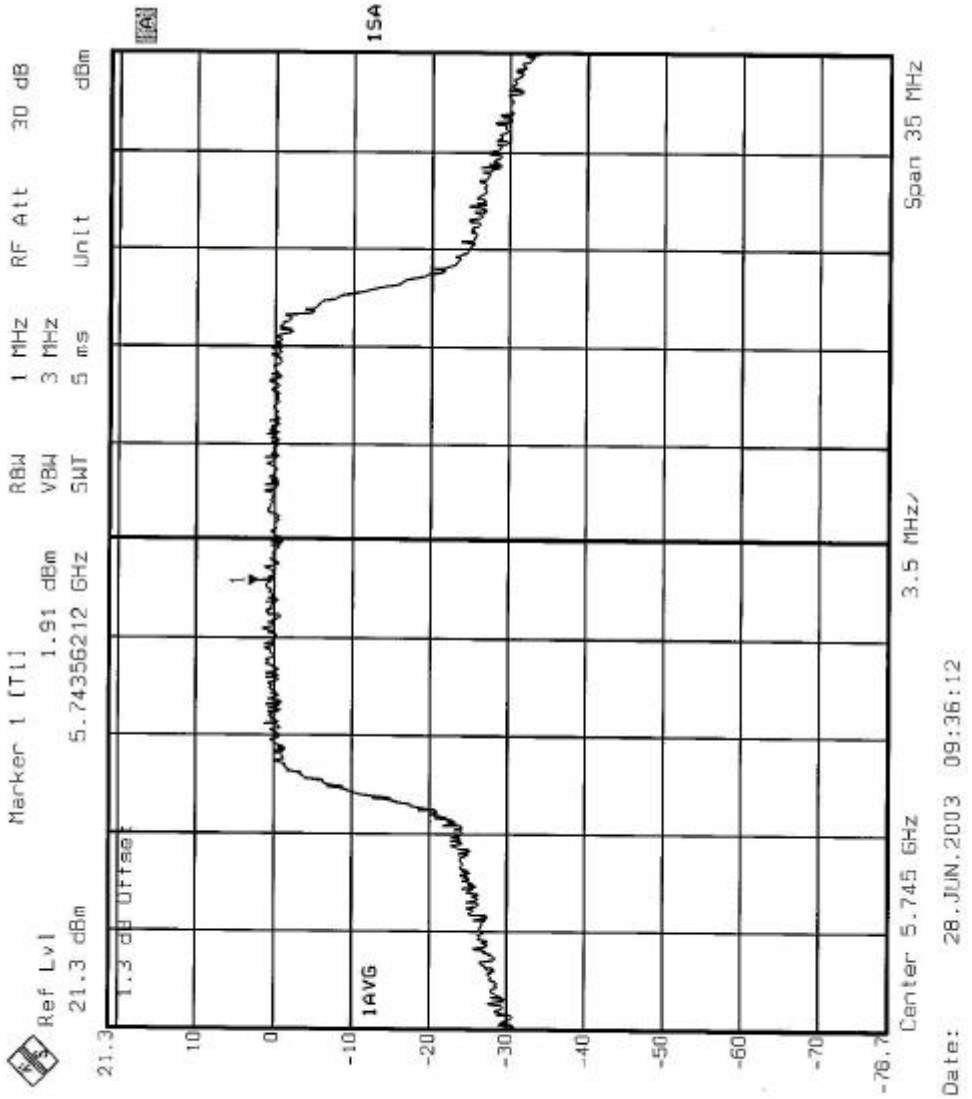
CHANNEL 5


Marker 1 [T1]
-0.14 dBm
5.25786072 GHz
RBW 1 MHz
VBW 3 MHz
SWT 5 ms
RF Att 30 dB
Unit dBm
Ref Lvl
21.3 dBm
1.3 dB Offset
1AV6
1SA
Center 5.26 GHz
3.5 MHz/
Span 35 MHz
Date: 28.JUN.2003 09:34:55

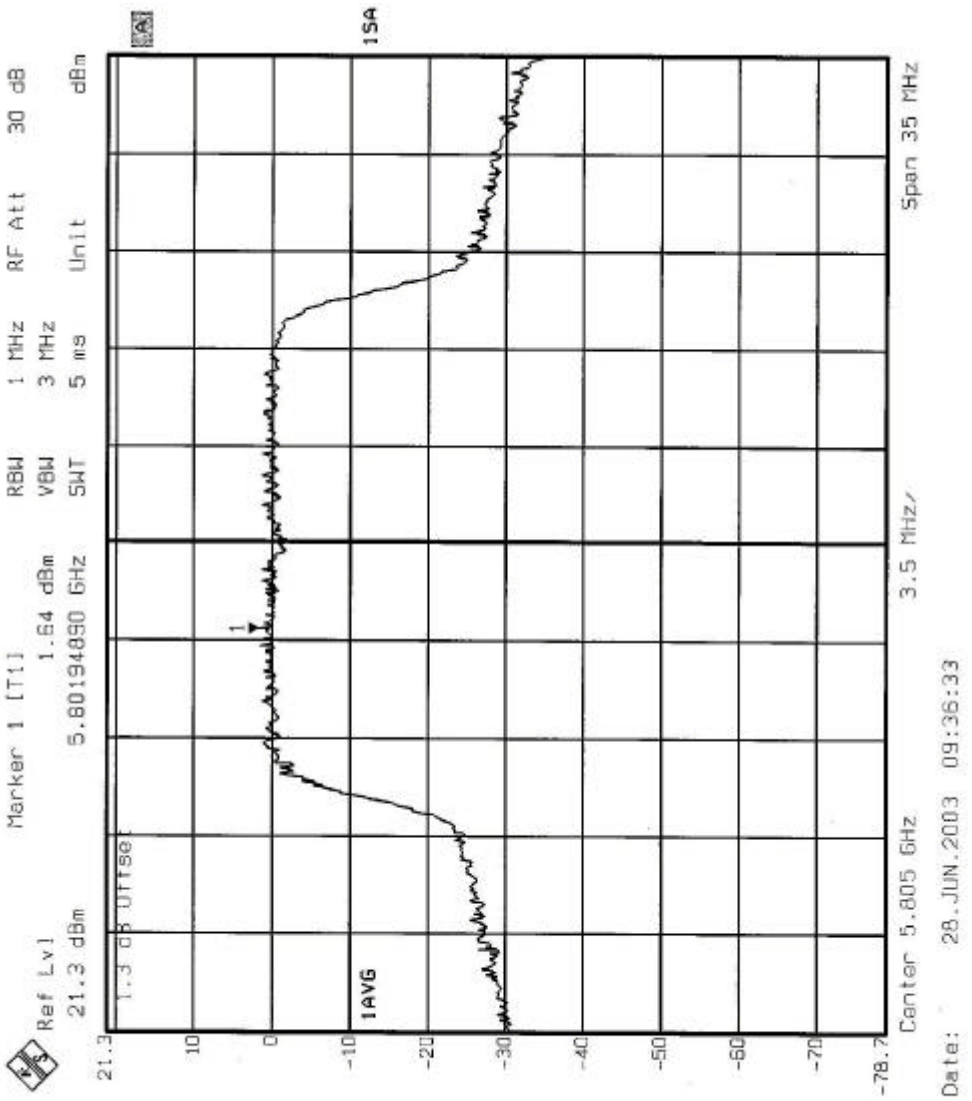
CHANNEL 8


Ref Lvl
21.3 dBm
1.3 dB Offset
Marker 1 [T1]
0.01 dBm
5.32284068 GHz
RBW 1 MHz
VBW 3 MHz
SWT 5 ms
RF Att 30 dB
Unit dBm
1SA
PRN
1AVG
Center 5.32 GHz
3.5 MHz/
Span 35 MHz
Date: 28.JUN.2003 09:35:22

CHANNEL 9


Ref Lvl
21.3 dBm
1.3 dB Offset
Marker 1 [T1]
1.91 dBm
5.74356212 GHz
RBW 1 MHz
VBW 3 MHz
SWT 5 ms
RF Att 30 dB
Unit dBm
1AVG
1SA
Center 5.745 GHz
3.5 MHz/
Span 35 MHz
Date: 28.JUN.2003 09:36:12

CHANNEL 12


Ref Lvl
21.3 dBm
1.3 dB Offset
Marker 1 [T1]
1.64 dBm
5.80194890 GHz
RBW 1 MHz
VBW 3 MHz
SWT 5 ms
RF Att 30 dB
Unit dBm
1SA
1AVG
Center 5.805 GHz
3.5 MHz/
Span 35 MHz
Date: 28.JUN.2003 09:36:33

5.6 FREQUENCY STABILITY

5.6.1 LIMITS OF FREQUENCY STABILITY MEASUREMENT

The frequency tolerance of the carrier signal shall be maintained within +/- 0.02% of the operating frequency over a temperature variation of –30 degrees to 50 degrees C at normal supply voltage, and for a variation in the primary supply voltage from 85% to 115% of the rated supply voltage at a temperature of 20 degrees C.

5.6.2 TEST INSTRUMENTS

Description & Manufacturer	Model No.	Serial No.	Calibrated Until
ANRITSU SPECTRUM ANALYZER	MS2667C	M10281	April 10, 2004
WIT STANDARD TEMPERATURE AND HUMIDITY CHAMBER	TH-4S-C	W901030	Jun. 24, 2004

NOTE: The calibration interval of the above test instruments is 12 months and the calibrations are traceable to NML/ROC and NIST/USA.

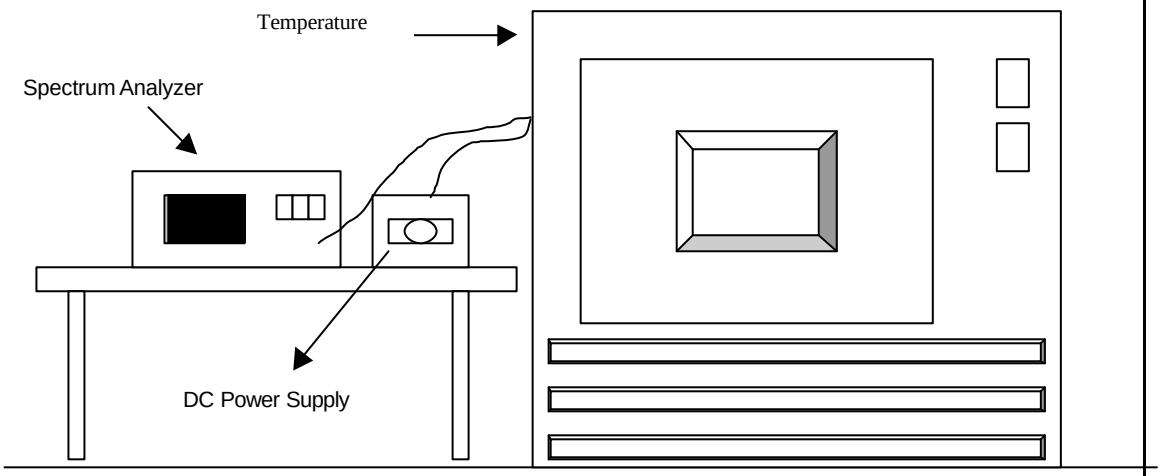
5.6.3 TEST PROCEDURE

1. The EUT was placed inside the environmental test chamber and powered by nominal DC voltage.
2. Turn the EUT on and couple its output to a spectrum analyzer.
3. Turn the EUT off and set the chamber to the highest temperature specified.
4. Allow sufficient time (approximately 30 min) for the temperature of the chamber to stabilize, turn the EUT on and measure the operating frequency after 2, 5, and 10 minutes.
5. Repeat step 2 and 3 with the temperature chamber set to the lowest temperature.
6. The test chamber was allowed to stabilize at +20 degree C for a minimum of 30 minutes. The supply voltage was then adjusted on the EUT from 85% to 115% and the frequency record.

5.6.4 DEVIATION FROM TEST STANDARD

No deviation

5.6.5 TEST SETUP



5.6.6 EUT OPERATING CONDITION

Same as Item 4.1.6

5.6.7 TEST RESULTS

Operating frequency: 5320MHz				Limit : ± 0.02%			
Temp. (°C)	Power supply (VDC)	2 minute		5 minute		10 minute	
		(MHz)	(%)	(MHz)	(%)	(MHz)	(%)
50	126.5	5320.0708	0.0013308	5320.0708	0.0013308	5320.0712	0.0013383
	110.0	5320.0708	0.0013308	5320.0708	0.0013308	5320.0712	0.0013383
	93.5	5320.0708	0.0013308	5320.0708	0.0013308	5320.0712	0.0013383
40	126.5	5320.0422	0.0007932	5320.0424	0.0007970	5320.0426	0.0008008
	110.0	5320.0422	0.0007932	5320.0424	0.0007970	5320.0426	0.0008008
	93.5	5320.0422	0.0007932	5320.0424	0.0007970	5320.0426	0.0008008
30	126.5	5320.0242	0.0004549	5320.0242	0.0004549	5320.0242	0.0004549
	110.0	5320.0242	0.0004549	5320.0242	0.0004549	5320.0242	0.0004549
	93.5	5320.0242	0.0004549	5320.0242	0.0004549	5320.0242	0.0004549
20	126.5	5320.0142	0.0002669	5320.0142	0.0002669	5320.0142	0.0002669
	110.0	5320.0142	0.0002669	5320.0142	0.0002669	5320.0142	0.0002669
	93.5	5320.0142	0.0002669	5320.0142	0.0002669	5320.0142	0.0002669
10	126.5	5320.0130	0.0002444	5320.0130	0.0002444	5320.0130	0.0002444
	110.0	5320.0130	0.0002444	5320.0130	0.0002444	5320.0130	0.0002444
	93.5	5320.0130	0.0002444	5320.0130	0.0002444	5320.0130	0.0002444
0	126.5	5320.0062	0.0001165	5320.0062	0.0001165	5320.0062	0.0001165
	110.0	5320.0062	0.0001165	5320.0062	0.0001165	5320.0062	0.0001165
	93.5	5320.0062	0.0001165	5320.0062	0.0001165	5320.0062	0.0001165
-10	126.5	5320.0070	0.0001316	5320.0070	0.0001316	5320.0070	0.0001316
	110.0	5320.0070	0.0001316	5320.0070	0.0001316	5320.0070	0.0001316
	93.5	5320.0070	0.0001316	5320.0070	0.0001316	5320.0070	0.0001316
-20	126.5	5320.0096	0.0001805	5320.0096	0.0001805	5320.0096	0.0001805
	110.0	5320.0096	0.0001805	5320.0096	0.0001805	5320.0096	0.0001805
	93.5	5320.0096	0.0001805	5320.0096	0.0001805	5320.0096	0.0001805
-30	126.5	5320.0108	0.0002030	5320.0108	0.0002030	5320.0108	0.0002030
	110.0	5320.0108	0.0002030	5320.0108	0.0002030	5320.0108	0.0002030
	93.5	5320.0108	0.0002030	5320.0108	0.0002030	5320.0108	0.0002030

5.7 BAND EDGES MEASUREMENT

5.7.1 TEST INSTRUMENTS

Description & Manufacturer	Model No.	Serial No.	Calibrated Until
SPECTRUM ANALYZER	FSEK30	100049	July 24, 2003

NOTE: The calibration interval of the above test instruments is 12 months and the calibrations are traceable to NML/ROC and NIST/USA.

5.7.2 TEST PROCEDURE

The transmitter output was connected to the spectrum analyzer via a low lose cable. Set both RBW and VBW of spectrum analyzer to 1MHz with suitable frequency span including 100 MHz bandwidth from band edge. The band edges was measured and recorded.

5.7.3 EUT OPERATING CONDITION

The software provided by client to enable the EUT under transmission condition continuously at specific channel frequencies individually.

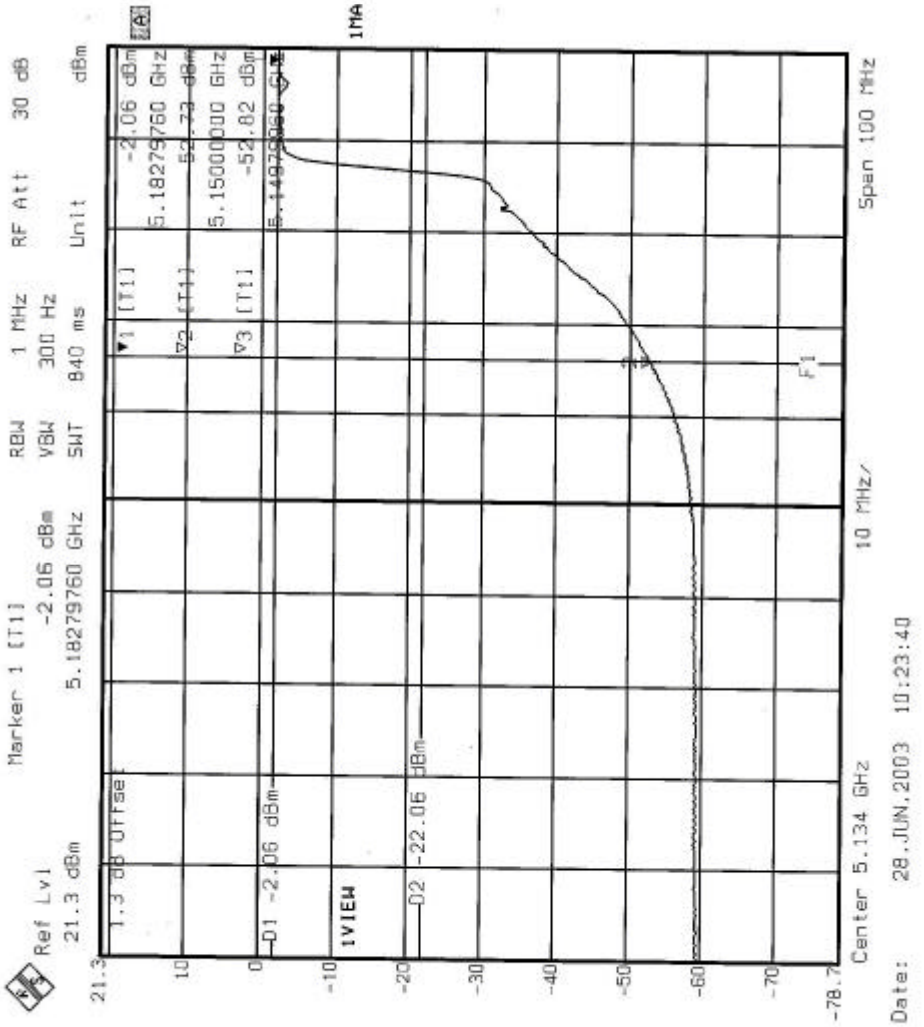
5.7.4 TEST RESULTS

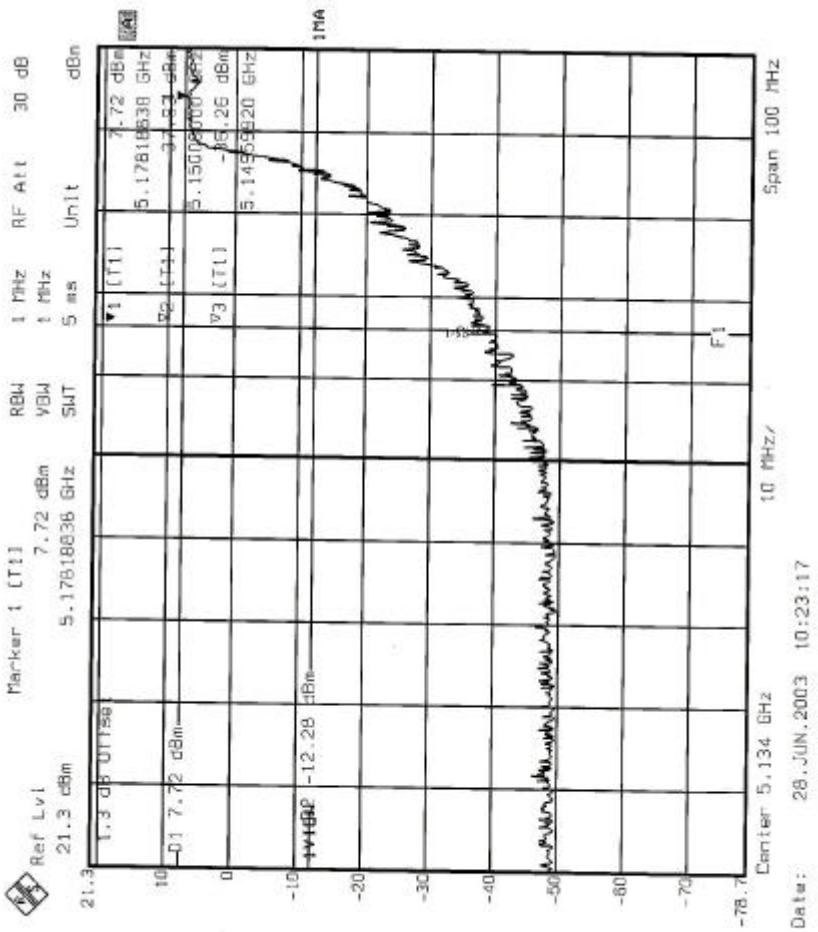
For signals in the restricted bands above and below the 5.15 to 5.35GHz allocated band a measurement was made of the amplitude of the spurious emissions with respect to the intentional signals. The relative amplitude, in dBc, was applied to the average and peak filed strength of the intentional signal made on the OATS to calculate the field strength of the unintentional signals.

The spectrum plots (Peak RBW=VBW=1MHz; Average RBW=1MHz, VBW=300Hz) are attached on the following 4 pages.

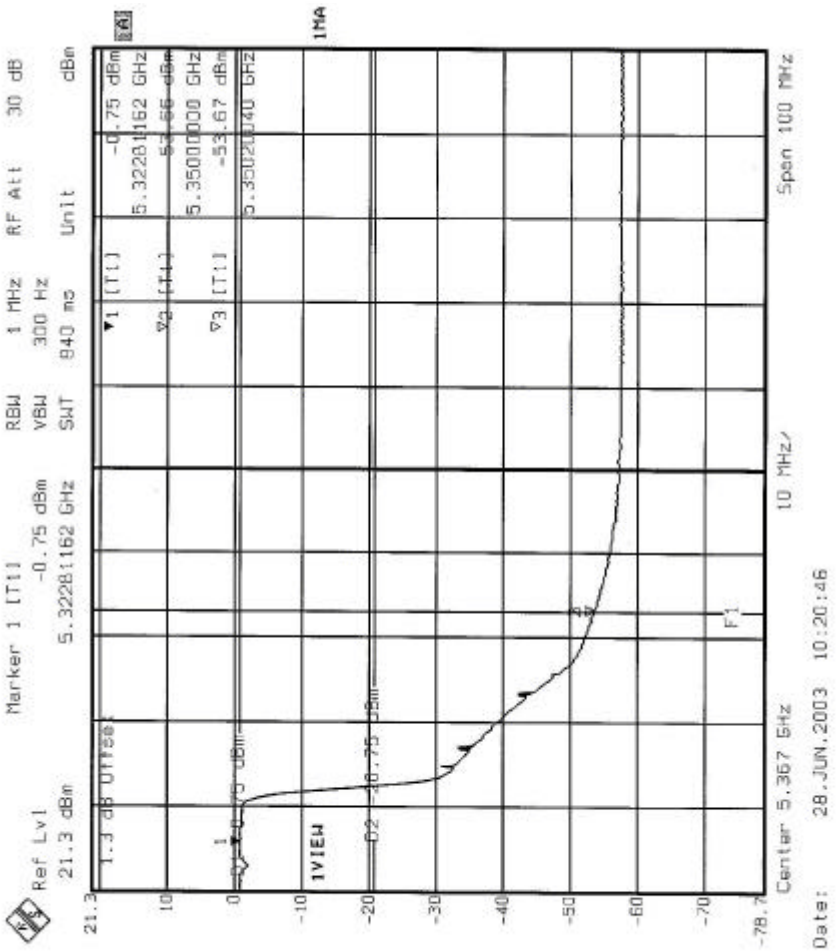
Channel 1 (5180 MHz)

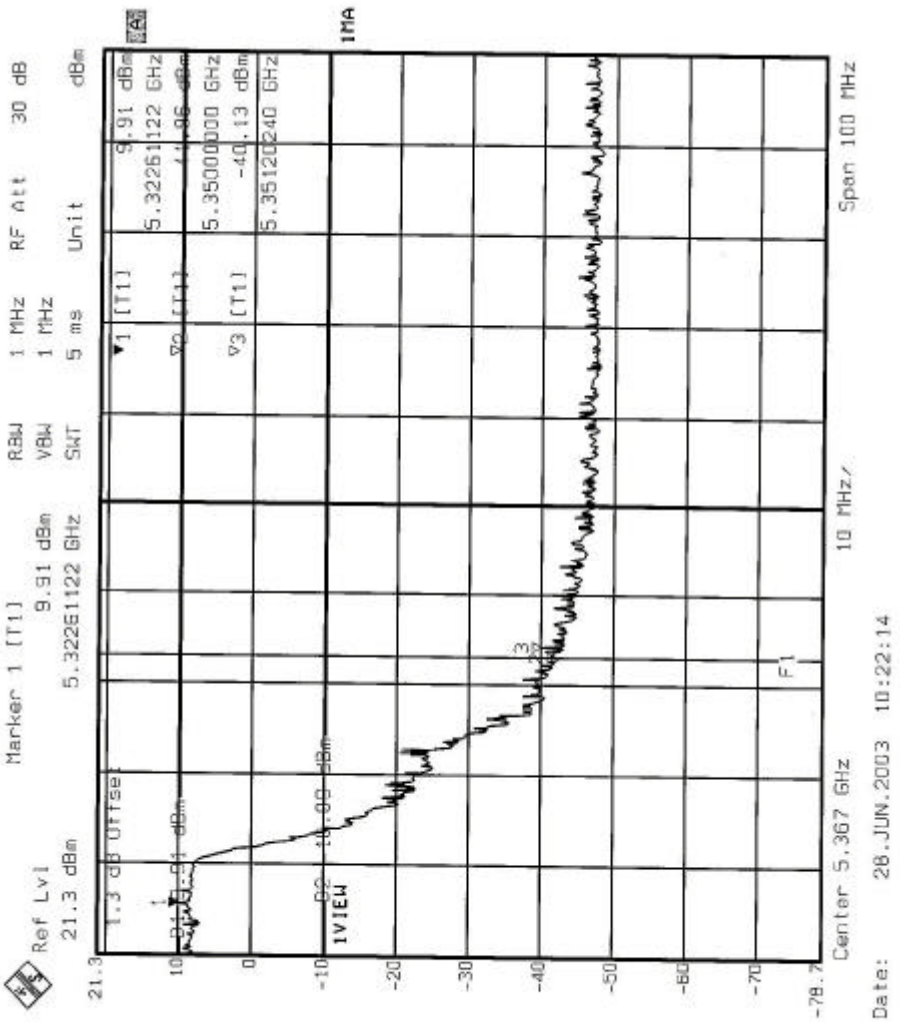
The band edge emission plot of OFDM technique on the following page shows 50.67dB delta between carrier maximum power and local maximum emission in restrict band (5.1500GHz). The emission of carrier strength list in the test result of channel 1 at the item 5.2.8 (Page 74) is 91.3dBuV/m, so the maximum field strength in restrict band is 91.3-50.67=40.63 dBuV/m which is under 54dBuV/m limit.




Ref Lvl
21.3 dBm
1.3 dB/ Offset
Marker 1 [T1]
7.72 dBm
5.178188038 GHz
RBW 1 MHz
VBW 1 MHz
SWT 5 ms
Unit dBm
RF Att 30 dB
1MA
T1 [T1] 7.72 dBm
5.178188038 GHz
T2 [T1] 37.83 dBm
5.150000000 GHz
T3 [T1] -65.26 dBm
5.149999920 GHz
D1 7.72 dBm
-12.28 dBm
F1
Center 5.134 GHz
10 MHz/
Span 100 MHz
Date: 28.JUN.2003 10:23:17

Channel 8 (5320 MHz)
The band edge emission plot of OFDM technique on the following page shows 52.91dB delta between carrier maximum power and local maximum emission in restrict band (5.3500GHz). The emission of carrier strength list in the test result of channel 1 at the item 5.2.8 (Page 74) is 94dBuV/m, so the maximum field strength in restrict band is 94-52.91=41.09dBuV/m which is under 54dBuV/m limit.




Marker 1 [T1]
9.91 dBm
5.32261122 GHz
Ref Lvl
21.3 dBm
1.3 dB Offset
RBW 1 MHz
VBW 1 MHz
SWT 5 ms
RF Att 30 dB
Unit dBm
1 [T1] 9.91 dBm
5.32261122 GHz
2 [T1]
3 [T1] -40.13 dBm
5.35120240 GHz
1MA
1VIEW
Center 5.367 GHz
10 MHz/
Span 100 MHz
Date: 28.JUN.2003 10:22:14

5.8 ANTENNA REQUIREMENT

5.8.1 STANDARD APPLICABLE

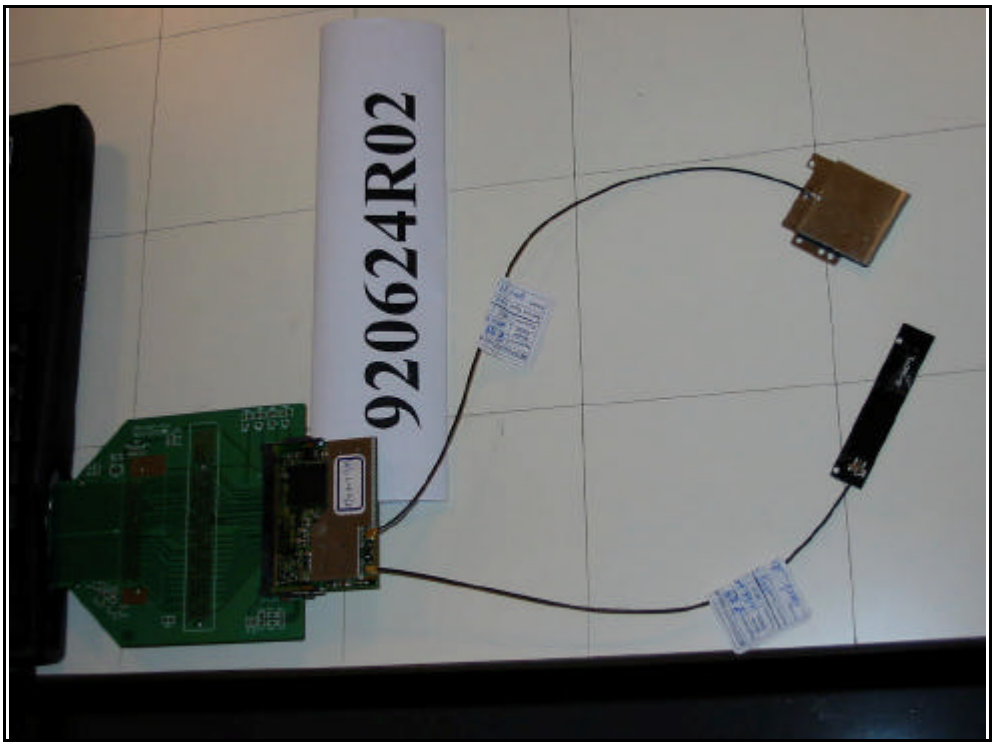
For intentional device, according to FCC 47 CFR Section 15.203, an intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device.
And according to FCC 47 CFR Section 15.407(a), if transmitting antennas of directional gain greater than 6dBi are used, the power shall be reduced by the amount in dB that the directional gain of the antenna exceeds 6dBi.

5.8.2 ANTENNA CONNECTED CONSTRUCTION

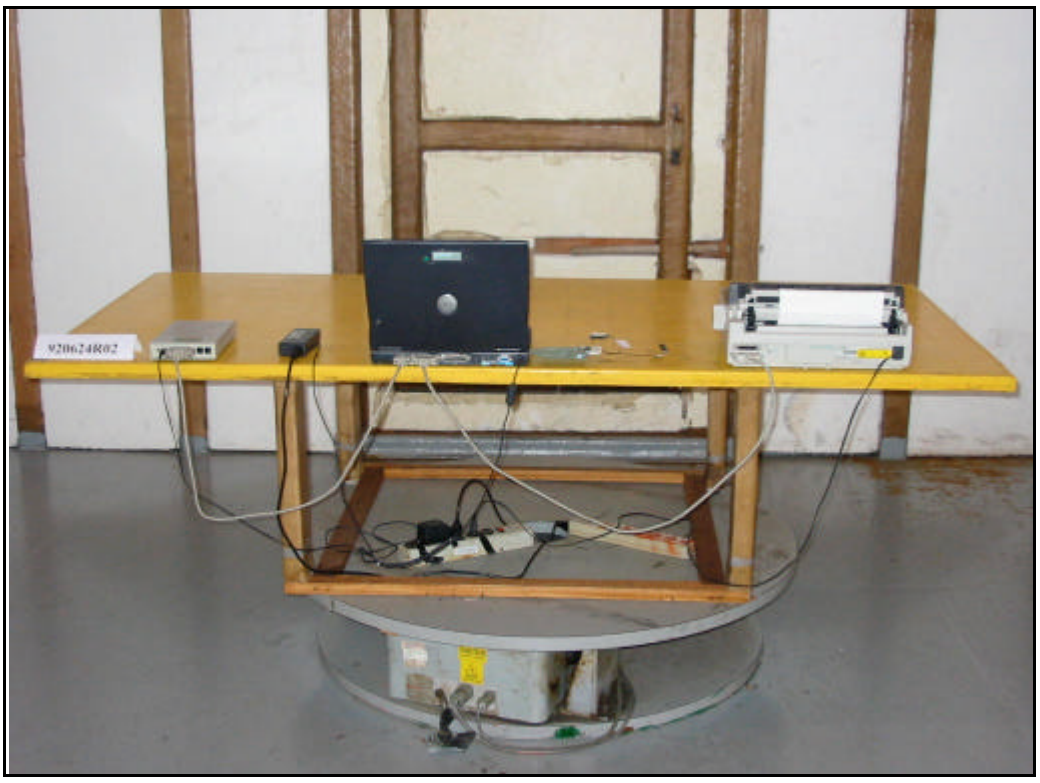
The antenna used in this product is printed antenna with UFL connector. The maximum Gain of the antenna is 2.8dBi.

6. PHOTOGRAPHS OF THE TEST CONFIGURATION

CONDUCTED EMISSION TEST


920624R02

RADIATED EMISSION TEST




920624R02

7. INFORMATION ON THE TESTING LABORATORIES

We, ADT Corp., were founded in 1988 to provide our best service in EMC and Safety consultation. Our laboratories are accredited and approved by the following approval agencies according to ISO/IEC 17025, Guide 25 or EN 45001:

USA	FCC, NVLAP, UL
Germany	TUV Rheinland
Japan	VCCI
New Zealand	MoC
Norway	NEMKO
R.O.C.	BSMI, DGT, CNLA

Copies of accreditation certificates of our laboratories obtained from approval agencies can be downloaded from our web site: www.adt.com.tw/index.5/phtml.

If you have any comments, please feel free to contact us at the following:

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Fax: 886-2-26052943

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Fax: 886-35-935342

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Lin Kou RF&Telecom Lab
Tel: 886-3-3270910
Fax: 886-3-3270892

Email: service@mail.adt.com.tw
Web Site: www.adt.com.tw

The address and road map of all our labs can be found in our web site also.